

AUTOMATING CYBER-PHYSICAL SECURITY VERIFICATION IN THE SOC DESIGN FLOW

Valentin Peltier, Product Marketing Manager

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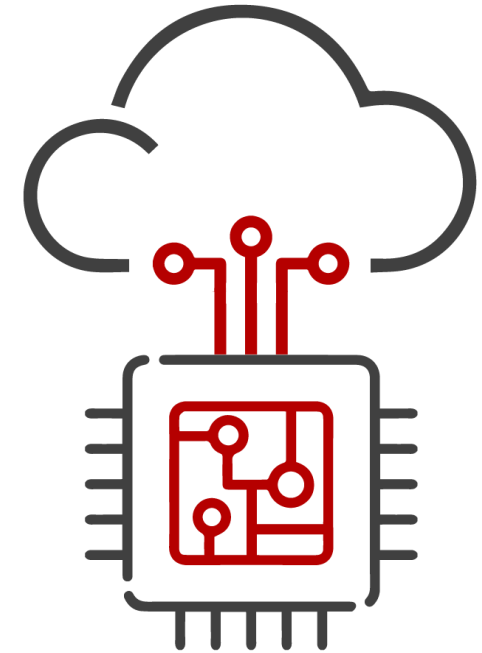
1. INTRODUCTION

IoT devices being interconnected, each and every object could be a threat for the whole network.

Therefore, the security of the objects or the devices with their lifecycle management is key, and so is their data. To ensure the integrity of this data, the whole system must be secured and managed. **Trusted devices enable trusted data.**

Secure-IC partners with its clients to provide them with the best end-to-end cybersecurity solutions for embedded systems and connected objects, **from Chip to Cloud**

ONE DAY, **SECURITY** WILL
BE WORTH MORE THAN
THE DEVICES





2. ABOUT PHYSICAL SECURITY

CRYPTOGRAPHY IS ROBUST, BUT...

Cryptography is robust but **physical attack** are here...

- **Side-Channel Analysis (SCA)**
- **Fault Injection Analysis (FIA)**
- Cache-Timing Analysis
- Reverse Engineering
- Hardware Trojan
- ...



Side-Channel Analysis

- Introduced in the 1990s by Paul Kocher*, an American cryptographer
- Recover secret keys by **measuring the execution time**
- Physical attacks was born!

**Paul Kocher, 1996, Timing Attacks on Implementations of Diffie-Hellman, RSA, DSS, and Other Systems*

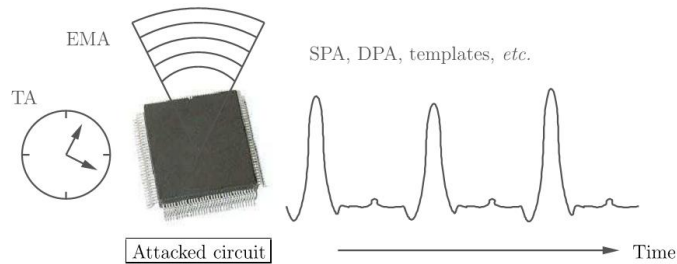
Fault Injection Analysis

- Initially used in hardware testing & reliability engineering, observing how system respond
→ safety-oriented
- Evolution into a **security-focused** methodology in the 1990s**

- R. Anderson & M. Kuhn, 1996, *Tamper Resistance - a Cautionary Note*
- D. Boneh, R. DeMillo, & R. Lipton, 1997, *On the importance of checking cryptographic protocols for faults*
- E. Biham & A. Shamir, 1997, *Differential fault analysis of secret key cryptosystems*

Side-Channel Analysis

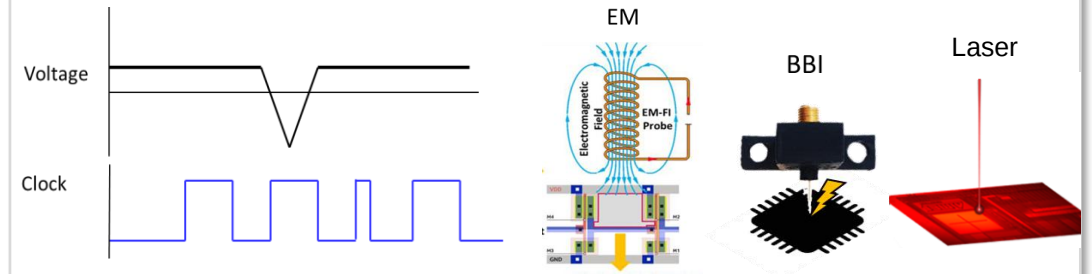
- **Measure execution activity** of sensitive data into embedded system



- All these characteristics become a potential leakage

Fault Injection Analysis

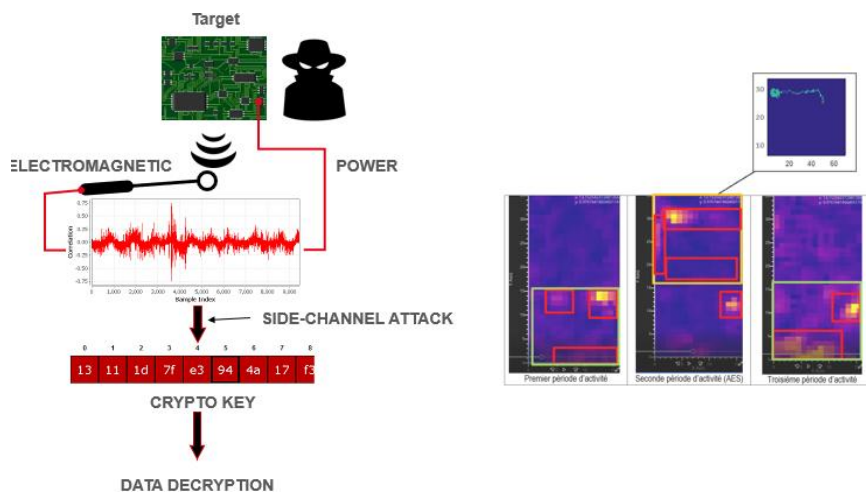
- **Disturb** embedded system **during execution**



- Injecting faults at different level:
 - Physical (memory, transistors, logic gates)
 - Micro-Code (skip/jump instruction, read/write)
 - Code (IO/crypto routines, loop statement)

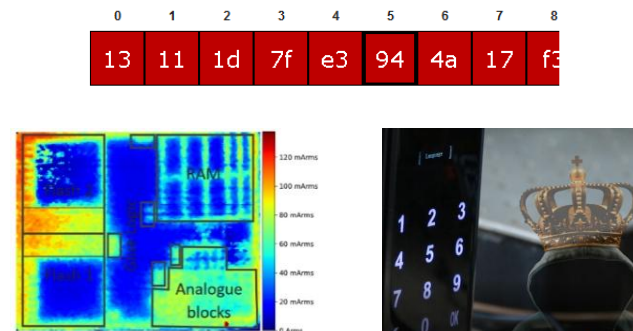
Side-Channel Analysis

- Secret Key Recovery
- Reverse Engineering
- ...



Fault Injection Analysis

- Denial of Service
- Privilege Escalation
- Secret Recovery
- Reverse Engineering
- ...





(2025 update in progress)

- MIHW 2021: the first list **focused on hardware security**
- Created by the Hardware CWE SIG (experts from industry, academia, and government)
- **CWE-1300 Improper Protection of Physical Side Channels**
- **CWE-1247 Improper Protection Against Voltage and Clock Glitches**
- **CWE-1332 Improper Handling of Faults that Lead to Instruction Skips**

- And there are many others...
 - CWE-1319: Improper Protection against Electromagnetic Fault Injection
 - CWE-1384: Improper Handling of Physical or Environmental Conditions
 - ...

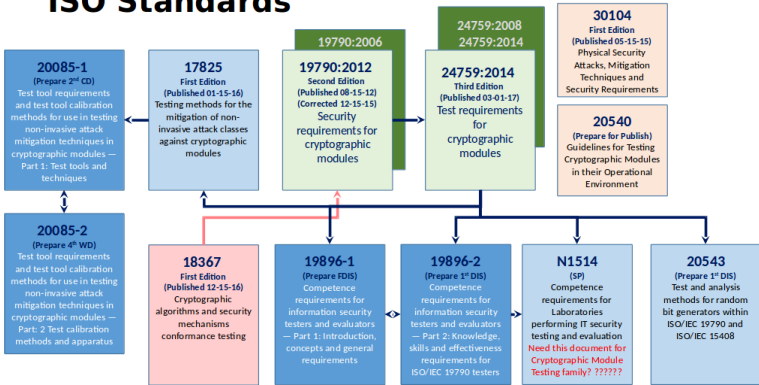


Common Criteria & Vulnerability Assessment

Range of values* *final attack potential = identification + exploitation	TOE resistant to attackers with attack potential of:	Analyses to be carried out in Secure-IC tools (Catalyzer/Virtualyzer/Analyzer)	Corresponding AVA_VAN	Corresponding EAL
0-15	No rating	No analysis required	AVA_VAN.1: vulnerability survey	EAL 1
16-20	Basic	SPA (Single trace analysis)	AVA_VAN.2: vulnerability analysis	EAL2/3
21-24	Enhanced-Basic	DPA ([1st-order] Differential analysis)	AVA_VAN.3: focused vulnerability analysis	EAL 4
25-30	Moderate	High-order analysis	AVA_VAN.4: methodical vulnerability	EAL 5 (or4+) analysis
31 and above	High	All abovementioned analysis, plus: collision-analysis, stochastic analysis, mutual information analysis, template attack, machine- learning attacks, deep-learning attack	AVA_VAN.5: advanced methodical vulnerability analysis	EAL 6/7 (or 5+)

FIPS 140-3 is transitioning to ISO/IEC 19790

Cryptographic Module Testing Family- ISO Standards



ISO 17825

Table 1 — Associations between non-invasive attack methods and security functions covered by this International Standard

Security functions		Non-invasive attack methods		
		SPA/SEMA	DPA/DEMA	TA
Symmetric-Key	AES	A	A	A
	Triple-DES	A	A	A
	Stream Ciphers	A	A	A
Asymmetric-Key	Plain RSA (Key wrapping)	A	A	A
	RSA PKCS#1 v1.5	A	A	A
	RSA PKCS#1 v2.1	NA	NA	A
	DSA	A	A	A
	ECDSA	A	A	A
Hashing mechanisms	SHA	A	NA	NA
RNG and RBG	Deterministic	A	NA	NA
	Non-deterministic	A	NA	NA



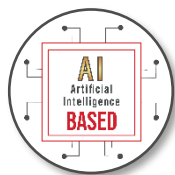
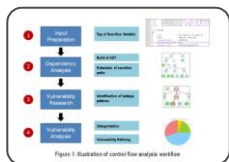
3. VERIFICATION TOOLS & AUTOMATION

ALONG DESIGN FLOW & V-CYCLE

```
29 'use strict';
30
31 var highlight = function($element, pattern) {
32   if (typeof pattern === 'string' && (pattern.length > 0)) {
33     var regex = (typeof pattern === 'string') ? new RegExp(pattern, 'g') : pattern;
34
35     var highlight = function(node) {
36       var skip = 0;
37       if (node.nodeType === 3) {
38         var pos = node.data.search(regex);
39         if (pos >= 0 && node.data.length > 0) {
40           var match = node.data.match(regex);
41           var spannode = document.createElement("span");
42           spannode.className = 'highlight';
43           var middlebit = node.splitText(pos);
44           var endbit = middlebit.splitText(match[0].length);
45           var middleclone = middlebit.cloneNode(true);
46           spannode.appendChild(middleclone);
47           spannode.parentNode.replaceChild(spannode, endbit);
48         }
49       }
50     };
51     $element.find('p').each(function() {
52       highlight(this);
53     });
54   }
55 }
```



SCA at Static Level

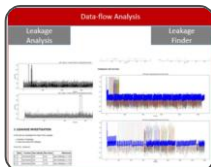


- Code source (C/C++) verification

- Timing vulnerability detection & warning (conditional branch, array indexation, ...)

```
for i = k - 1 to 0 do
  a ← a2 mod n
  if di = 1 then
    a ← a × m mod n
return a
```

SCA at Dynamic Level



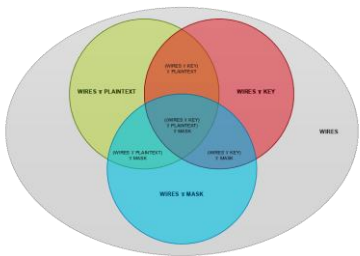
- Binary execution monitoring (emulation)

- Register dumping to rebuild activity (EM/Power traces)
- Cryptanalysis methodologies (NICV, T-TEST, TVLA, CPA, DPA, SPA...)

- Leakage location on design code

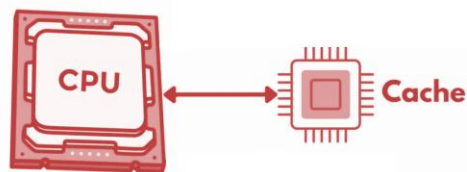
File	Function	Line	Register	Sample
aes-challenge-c.c	ark_sb_rnd	95	eflags	207
aes-challenge-c.c	ark_sb_rnd	95	eflags	211
aes-challenge-c.c	ark_sb_rnd	95	eflags	274

Masking Scheme Checker



- **Verify the masking protection coverage**
- Wires & mask dependencies
- Correlation on *protected* vs. *unprotected* databases

Cache-Timing Analysis



- **Mesures memory access times (cache vs. RAM)**
- Differences leak sensitive data
- e.g. Time taken during AES encryption is key dependent

Binary Analysis



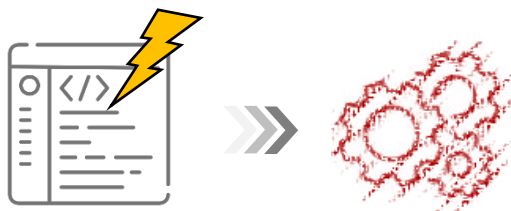
- **Firmware analysis for security checkup**
- System (filesystem, system users & utilities)
- Sensitive files (certificates, private keys)
- Security level (system calls, code practice...)

Crypto Misuse



- **Cryptographic integration checkup**
- Detect cryptography misuse in a crypto API
- Rule-based analysis engine
- e.g. PKCS11, OpenSSL, Secure-IC iSE neo...

FIA at Static Injection Level



- **Code source (C/C++) modification**
 - Manual modification before compilation (code instruction, global variable)
 - Output execution analysis

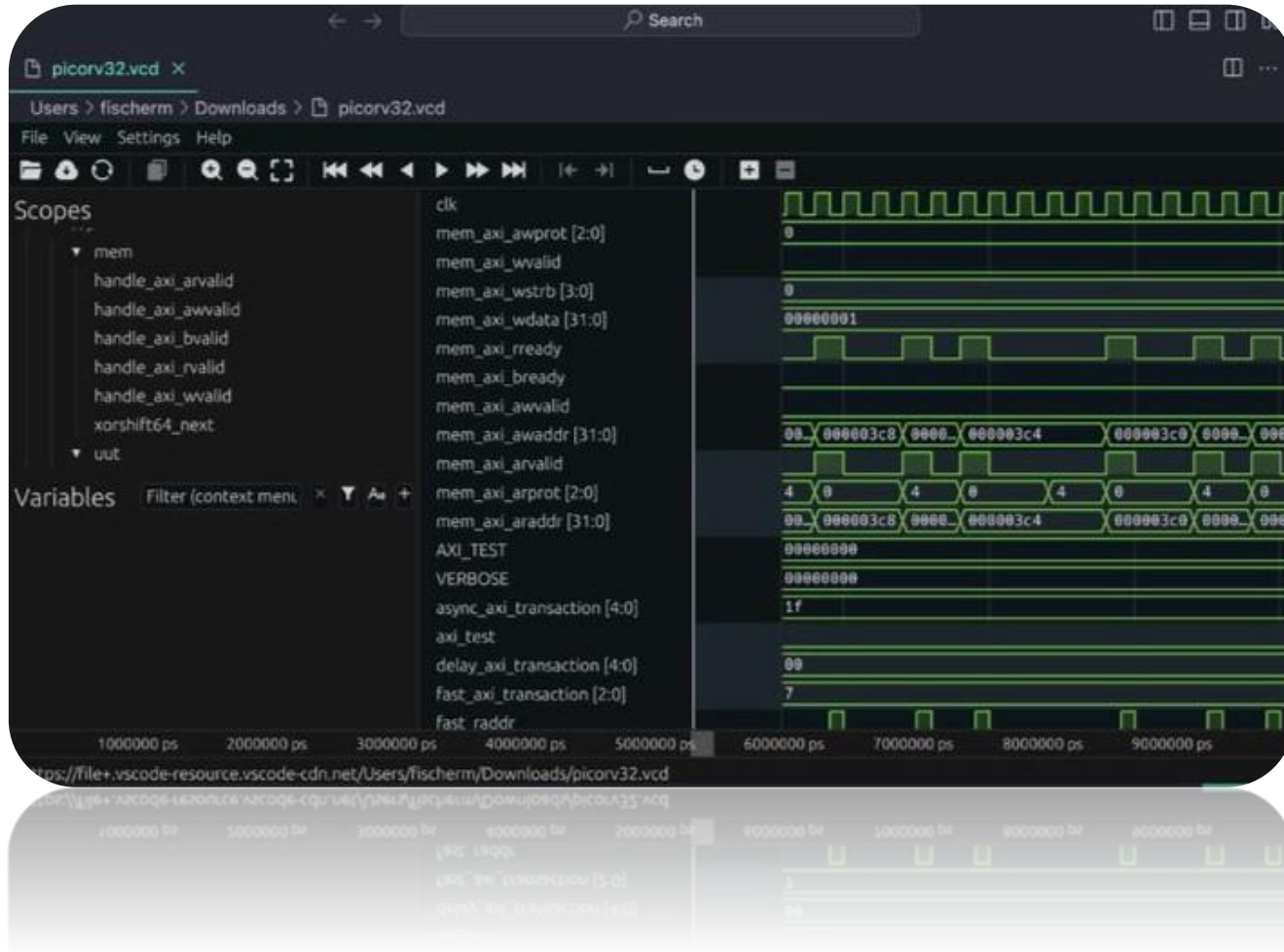
FIA at Dynamic Injection Level

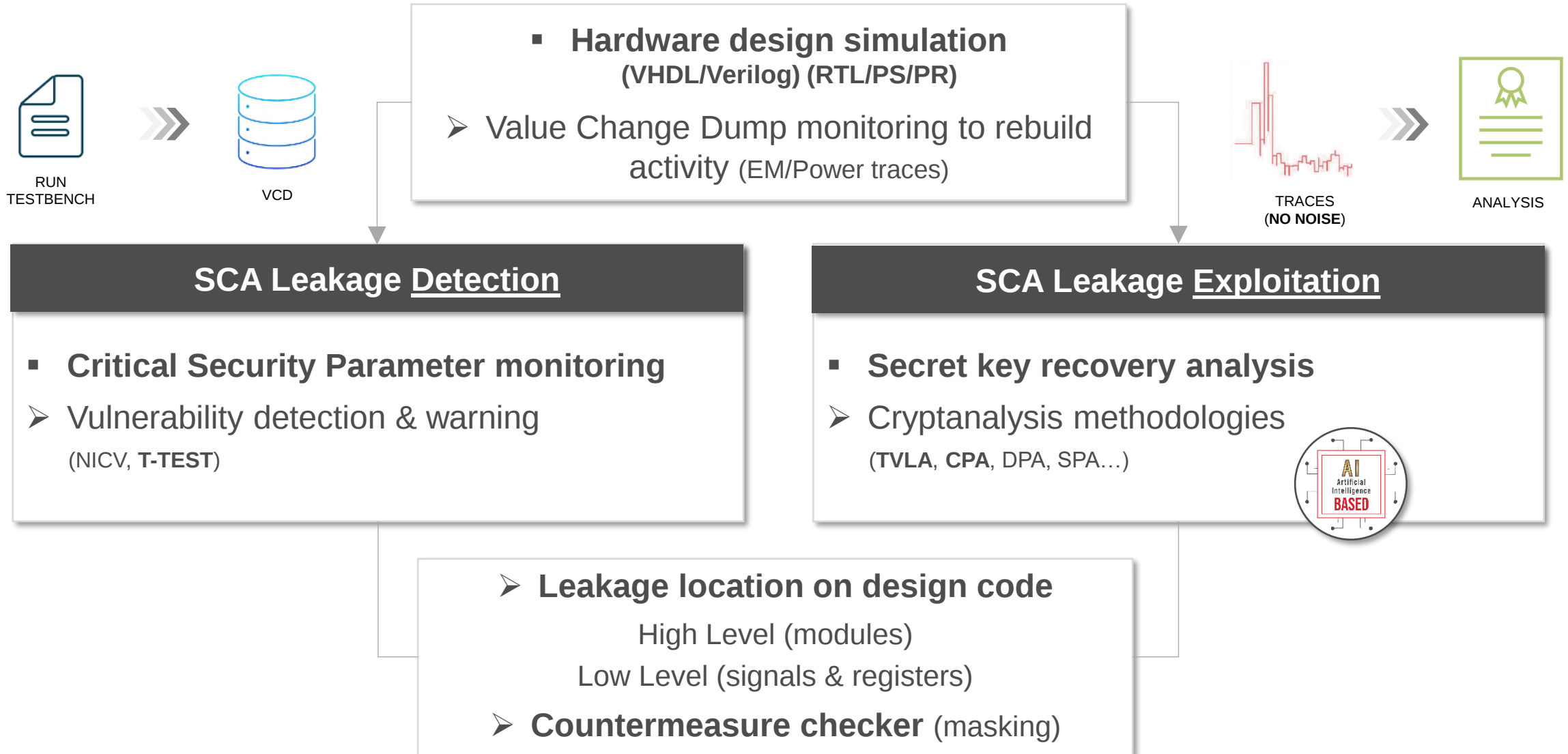


- **Binary execution disturbance (emulation)**
 - Automated modification during emulation (register corruption, instruction jump/bypass)
 - Output execution analysis

➤ Leakage location on design code

File	Function	Line	Register	Sample
aes-challenge-c.c	ark_sb_rnd	95	eflags	207
aes-challenge-c.c	ark_sb_rnd	95	eflags	211
aes-challenge-c.c	ark_sb_rnd	95	eflags	274





- Hardware design simulation (VHDL/Verilog) (RTL/PS/PR) 

FIA Clock Glitch



- Glitch fault model applied to the clock
- CLK signal modification

FIA ElectroMagnetic



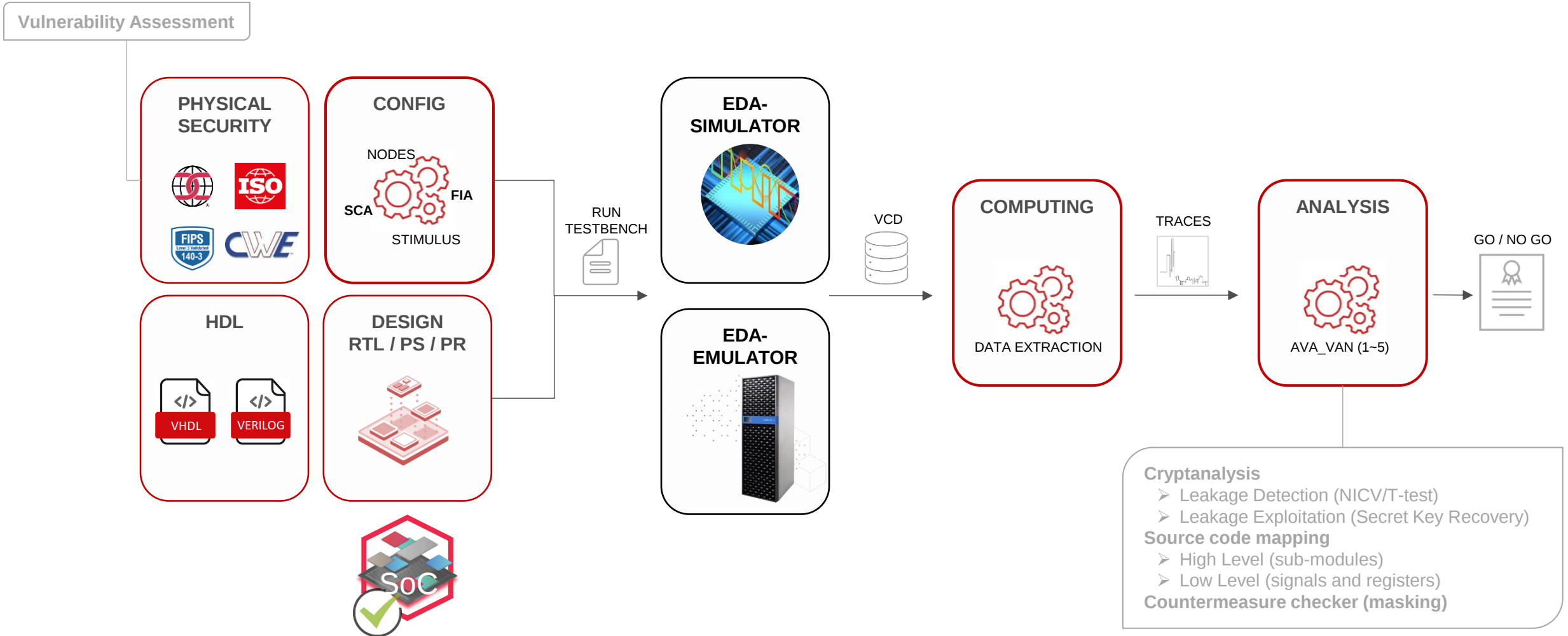
- EM fault models applied to any register/signal
- Bit freeze, Stuck at 1 (or 0)

FIA Laser



- Laser fault models applied to any register/signal
- Bit flip, Bit set, Bit reset

- **Cryptanalysis: secret key recovery**
(Differential Fault Analysis)



Abstract red geometric shapes, including rectangles and parallelograms, arranged in a dynamic, overlapping pattern on the left side of the slide.

4. CONCLUSION

- **Security must be verified—not just designed**
 - Side-Channel and Fault Injection analysis are critical threats requiring proactive mitigation from RTL to silicon.
- **Automation enables true lifecycle coverage**
 - Embedding physical analysis (SCA, FIA) into standard verification flows ensures early detection and validation throughout the SoC development process.
- **Accelerate compliance and reduce risk**
 - Supports faster certification (CC, ISO, CAVP, FIPS 140-3) and reduces manual effort for design teams up to security sign-off.



5. SECURE-IC'S SOLUTIONS

3 TOOLS FOR SECURITY VERIFICATION ALONG DEVICE LIFECYCLE



DESIGN LIFE CYCLE

- **DEVICE
LAYER**



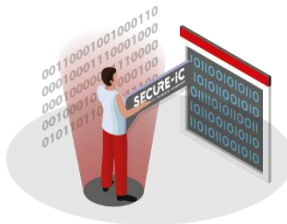
ANALYZR™

- **SOFTWARE
LAYER**



CATALYZR™

- **HARDWARE
LAYER**



VIRTUALYZR™

- **REAL DEVICE
EVALUATION**

- **SOFTWARE
VERIFICATION**

- **PRE-SILICON
VERIFICATION**

SECURITY LIFE CYCLE

FORMAL VERIFICATION

SIMULATION

EMULATION

DFS
in depth

**Functional
Analysis**

Jasper[™]
C/C++ Apps

C/C++

Jasper[™]
RTL Apps

RTL

SPV App

RTL

Xcelium[™]
Apps

RTL/PS/PR

Palladium[™]
Apps

RTL/PS/PR

Security Analysis
Data Flow based

**Physical
Security Analysis**

Data Manipulation based
(Common Criteria, FIPS, ISO/IEC)



CATALYZR[™]

Software design layer
C/C++



VIRTUALYZR[™]

Hardware design layer
RTL/PS/PR

**Secure-IC
Virtualyzr[™]**

RTL/PS/PR

**Secure-IC
Virtualyzr[™]**

RTL/PS/PR

**Secure-IC
Catalyzr[™]**

C/C++

THANK YOU FOR YOUR ATTENTION

CONTACTS

EMEA	sales-EMEA@secure-IC.com
APAC	sales-APAC@secure-IC.com
CHINA	sales-CHINA@secure-IC.com
JAPAN	sales-JAPAN@secure-IC.com
TAIWAN	sales-TAIWAN@secure-IC.com
AMERICAS	sales-US@secure-IC.com

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